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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	185000
Number of Logic Elements/Cells	490000
Total RAM Bits	46080000
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/5sgxma5n2f40c2n">https://www.e-xfl.com/product-detail/intel/5sgxma5n2f40c2n</a>

**Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 2 of 2)**

Symbol	Description	Minimum	Maximum	Unit
V <sub>CCD_FPLL</sub>	PLL digital power supply	−0.5	1.8	V
V <sub>CCA_FPLL</sub>	PLL analog power supply	−0.5	3.4	V
V <sub>I</sub>	DC input voltage	−0.5	3.8	V
T <sub>J</sub>	Operating junction temperature	−55	125	°C
T <sub>STG</sub>	Storage temperature (No bias)	−65	150	°C
I <sub>OUT</sub>	DC output current per pin	−25	40	mA

Table 4 lists the absolute conditions for the transceiver power supply for Stratix V GX, GS, and GT devices.

**Table 4. Transceiver Power Supply Absolute Conditions for Stratix V GX, GS, and GT Devices**

Symbol	Description	Devices	Minimum	Maximum	Unit
V <sub>CCA_GXBL</sub>	Transceiver channel PLL power supply (left side)	GX, GS, GT	−0.5	3.75	V
V <sub>CCA_GXBR</sub>	Transceiver channel PLL power supply (right side)	GX, GS	−0.5	3.75	V
V <sub>CCA_GTBR</sub>	Transceiver channel PLL power supply (right side)	GT	−0.5	3.75	V
V <sub>CCHIP_L</sub>	Transceiver hard IP power supply (left side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCHIP_R</sub>	Transceiver hard IP power supply (right side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCHSSI_L</sub>	Transceiver PCS power supply (left side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCHSSI_R</sub>	Transceiver PCS power supply (right side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCR_GXBL</sub>	Receiver analog power supply (left side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCR_GXBR</sub>	Receiver analog power supply (right side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCR_GTBR</sub>	Receiver analog power supply for GT channels (right side)	GT	−0.5	1.35	V
V <sub>CCT_GXBL</sub>	Transmitter analog power supply (left side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCT_GXBR</sub>	Transmitter analog power supply (right side)	GX, GS, GT	−0.5	1.35	V
V <sub>CCT_GTBR</sub>	Transmitter analog power supply for GT channels (right side)	GT	−0.5	1.35	V
V <sub>CCL_GTBR</sub>	Transmitter clock network power supply (right side)	GT	−0.5	1.35	V
V <sub>CCH_GXBL</sub>	Transmitter output buffer power supply (left side)	GX, GS, GT	−0.5	1.8	V
V <sub>CCH_GXBR</sub>	Transmitter output buffer power supply (right side)	GX, GS, GT	−0.5	1.8	V

#### Maximum Allowed Overshoot and Undershoot Voltage

During transitions, input signals may overshoot to the voltage shown in Table 5 and undershoot to −2.0 V for input currents less than 100 mA and periods shorter than 20 ns.

### I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

**Table 9. I/O Pin Leakage Current for Stratix V Devices <sup>(1)</sup>**

Symbol	Description	Conditions	Min	Typ	Max	Unit
$I_I$	Input pin	$V_I = 0 \text{ V to } V_{CCIO\text{MAX}}$	-30	—	30	$\mu\text{A}$
$I_{OZ}$	Tri-stated I/O pin	$V_O = 0 \text{ V to } V_{CCIO\text{MAX}}$	-30	—	30	$\mu\text{A}$

**Note to Table 9:**

(1) If  $V_O = V_{CCIO}$  to  $V_{CCIO\text{MAX}}$ , 100  $\mu\text{A}$  of leakage current per I/O is expected.

### Bus Hold Specifications

Table 10 lists the Stratix V device family bus hold specifications.

**Table 10. Bus Hold Parameters for Stratix V Devices**

Parameter	Symbol	Conditions	V <sub>CCIO</sub>										Unit
			1.2 V		1.5 V		1.8 V		2.5 V		3.0 V		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I <sub>SUSL</sub>	V <sub>IN</sub> > V <sub>IL</sub> (maximum)	22.5	—	25.0	—	30.0	—	50.0	—	70.0	—	μA
High sustaining current	I <sub>SUSH</sub>	V <sub>IN</sub> < V <sub>IH</sub> (minimum)	−22.5	—	−25.0	—	−30.0	—	−50.0	—	−70.0	—	μA
Low overdrive current	I <sub>ODL</sub>	0V < V <sub>IN</sub> < V <sub>CCIO</sub>	—	120	—	160	—	200	—	300	—	500	μA
High overdrive current	I <sub>ODH</sub>	0V < V <sub>IN</sub> < V <sub>CCIO</sub>	—	−120	—	−160	—	−200	—	−300	—	−500	μA
Bus-hold trip point	V <sub>TRIP</sub>	—	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

### On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

**Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices <sup>(1)</sup> (Part 1 of 2)**

Symbol	Description	Conditions	Calibration Accuracy				Unit
			C1	C2,I2	C3,I3, I3YY	C4,I4	
25- $\Omega$ $R_S$	Internal series termination with calibration (25- $\Omega$ setting)	$V_{\text{CCIO}} = 3.0, 2.5, 1.8, 1.5, 1.2 \text{ V}$	$\pm 15$	$\pm 15$	$\pm 15$	$\pm 15$	%

**Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 2 of 2) <sup>(1)</sup>**

Symbol	Description	V <sub>CCIO</sub> (V)	Typical	Unit
dR/dT	OCT variation with temperature without recalibration	3.0	0.189	%/ <sup>o</sup> C
		2.5	0.208	
		1.8	0.266	
		1.5	0.273	
		1.2	0.317	

**Note to Table 13:**

(1) Valid for a V<sub>CCIO</sub> range of  $\pm 5\%$  and a temperature range of 0° to 85°C.

**Pin Capacitance**

Table 14 lists the Stratix V device family pin capacitance.

**Table 14. Pin Capacitance for Stratix V Devices**

Symbol	Description	Value	Unit
C <sub>IOTB</sub>	Input capacitance on the top and bottom I/O pins	6	pF
C <sub>IOLR</sub>	Input capacitance on the left and right I/O pins	6	pF
C <sub>OUTFB</sub>	Input capacitance on dual-purpose clock output and feedback pins	6	pF

**Hot Socketing**

Table 15 lists the hot socketing specifications for Stratix V devices.

**Table 15. Hot Socketing Specifications for Stratix V Devices**

Symbol	Description	Maximum
I <sub>IOPIN</sub> (DC)	DC current per I/O pin	300 $\mu$ A
I <sub>IOPIN</sub> (AC)	AC current per I/O pin	8 mA <sup>(1)</sup>
I <sub>XCVR-TX</sub> (DC)	DC current per transceiver transmitter pin	100 mA
I <sub>XCVR-RX</sub> (DC)	DC current per transceiver receiver pin	50 mA

**Note to Table 15:**

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns,  $|I_{IOPIN}| = C \, dv/dt$ , in which C is the I/O pin capacitance and dv/dt is the slew rate.

## Internal Weak Pull-Up Resistor

Table 16 lists the weak pull-up resistor values for Stratix V devices.

**Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices <sup>(1), (2)</sup>**

Symbol	Description	V <sub>CCIO</sub> Conditions (V) <sup>(3)</sup>	Value <sup>(4)</sup>	Unit
R <sub>PU</sub>	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	kΩ
		2.5 ±5%	25	kΩ
		1.8 ±5%	25	kΩ
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	kΩ
		1.25 ±5%	25	kΩ
		1.2 ±5%	25	kΩ

### Notes to Table 16:

- (1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.
- (2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ.
- (3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V<sub>CCIO</sub>.
- (4) These specifications are valid with a ±10% tolerance to cover changes over PVT.

## I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V<sub>IH</sub> and V<sub>IL</sub>), output voltage (V<sub>OH</sub> and V<sub>OL</sub>), and current drive characteristics (I<sub>OH</sub> and I<sub>OL</sub>) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V<sub>OL</sub> and V<sub>OH</sub> values are valid at the corresponding I<sub>OH</sub> and I<sub>OL</sub>, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to “Glossary” on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012\_486.

**Table 17. Single-Ended I/O Standards for Stratix V Devices**

I/O Standard	V <sub>CCIO</sub> (V)			V <sub>IL</sub> (V)		V <sub>IH</sub> (V)		V <sub>OL</sub> (V)	V <sub>OH</sub> (V)	I <sub>OL</sub> (mA)	I <sub>OH</sub> (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
LVTTTL	2.85	3	3.15	−0.3	0.8	1.7	3.6	0.4	2.4	2	−2
LVC MOS	2.85	3	3.15	−0.3	0.8	1.7	3.6	0.2	V <sub>CCIO</sub> − 0.2	0.1	−0.1
2.5 V	2.375	2.5	2.625	−0.3	0.7	1.7	3.6	0.4	2	1	−1
1.8 V	1.71	1.8	1.89	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.45	V <sub>CCIO</sub> − 0.45	2	−2
1.5 V	1.425	1.5	1.575	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.25 * V <sub>CCIO</sub>	0.75 * V <sub>CCIO</sub>	2	−2
1.2 V	1.14	1.2	1.26	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.25 * V <sub>CCIO</sub>	0.75 * V <sub>CCIO</sub>	2	−2

**Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 2 of 7)**

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Spread-spectrum downspread	PCIe	—	0 to -0.5	—	—	0 to -0.5	—	—	0 to -0.5	—	%
On-chip termination resistors <sup>(21)</sup>	—	—	100	—	—	100	—	—	100	—	$\Omega$
Absolute $V_{MAX}$ <sup>(5)</sup>	Dedicated reference clock pin	—	—	1.6	—	—	1.6	—	—	1.6	V
	RX reference clock pin	—	—	1.2	—	—	1.2	—	—	1.2	
Absolute $V_{MIN}$	—	-0.4	—	—	-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	200	—	1600	mV
$V_{ICM}$ (AC coupled) <sup>(3)</sup>	Dedicated reference clock pin	1050/1000/900/850 <sup>(2)</sup>			1050/1000/900/850 <sup>(2)</sup>			1050/1000/900/850 <sup>(2)</sup>			mV
	RX reference clock pin	1.0/0.9/0.85 <sup>(4)</sup>			1.0/0.9/0.85 <sup>(4)</sup>			1.0/0.9/0.85 <sup>(4)</sup>			V
$V_{ICM}$ (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	250	—	550	mV
Transmitter REFCLK Phase Noise (622 MHz) <sup>(20)</sup>	100 Hz	—	—	-70	—	—	-70	—	—	-70	dBc/Hz
	1 kHz	—	—	-90	—	—	-90	—	—	-90	dBc/Hz
	10 kHz	—	—	-100	—	—	-100	—	—	-100	dBc/Hz
	100 kHz	—	—	-110	—	—	-110	—	—	-110	dBc/Hz
	$\geq 1$ MHz	—	—	-120	—	—	-120	—	—	-120	dBc/Hz
Transmitter REFCLK Phase Jitter (100 MHz) <sup>(17)</sup>	10 kHz to 1.5 MHz (PCIe)	—	—	3	—	—	3	—	—	3	ps (rms)
$R_{REF}$ <sup>(19)</sup>	—	—	1800 $\pm 1\%$	—	—	1800 $\pm 1\%$	—	—	1800 $\pm 1\%$	—	$\Omega$
<b>Transceiver Clocks</b>											
fixedclk clock frequency	PCIe Receiver Detect	—	100 or 125	—	—	100 or 125	—	—	100 or 125	—	MHz

Table 25 shows the approximate maximum data rate using the standard PCS.

**Table 25. Stratix V Standard PCS Approximate Maximum Date Rate <sup>(1)</sup>, <sup>(3)</sup>**

Mode <sup>(2)</sup>	Transceiver Speed Grade	PMA Width	20	20	16	16	10	10	8	8
		PCS/Core Width	40	20	32	16	20	10	16	8
FIFO	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
	2	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
		C3, I3, I3L core speed grade	9.8	9.0	7.84	7.2	5.3	4.7	4.24	3.76
	3	C1, C2, C2L, I2, I2L core speed grade	8.5	8.5	8.5	8.5	6.5	5.8	5.2	4.72
		I3YY core speed grade	10.3125	10.3125	7.84	7.2	5.3	4.7	4.24	3.76
		C3, I3, I3L core speed grade	8.5	8.5	7.84	7.2	5.3	4.7	4.24	3.76
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.8	4.2	3.84	3.44
Register	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
	2	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
		C3, I3, I3L core speed grade	9.8	9.0	7.92	7.2	4.9	4.5	3.96	3.6
	3	C1, C2, C2L, I2, I2L core speed grade	10.3125	10.3125	10.3125	10.3125	6.1	5.7	4.88	4.56
		I3YY core speed grade	10.3125	10.3125	7.92	7.2	4.9	4.5	3.96	3.6
		C3, I3, I3L core speed grade	8.5	8.5	7.92	7.2	4.9	4.5	3.96	3.6
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.4	4.1	3.52	3.28

**Notes to Table 25:**

- (1) The maximum data rate is in Gbps.
- (2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.
- (3) The maximum data rate is also constrained by the transceiver speed grade. Refer to Table 1 for the transceiver speed grade.

Figure 2 shows the differential transmitter output waveform.

**Figure 2. Differential Transmitter Output Waveform**

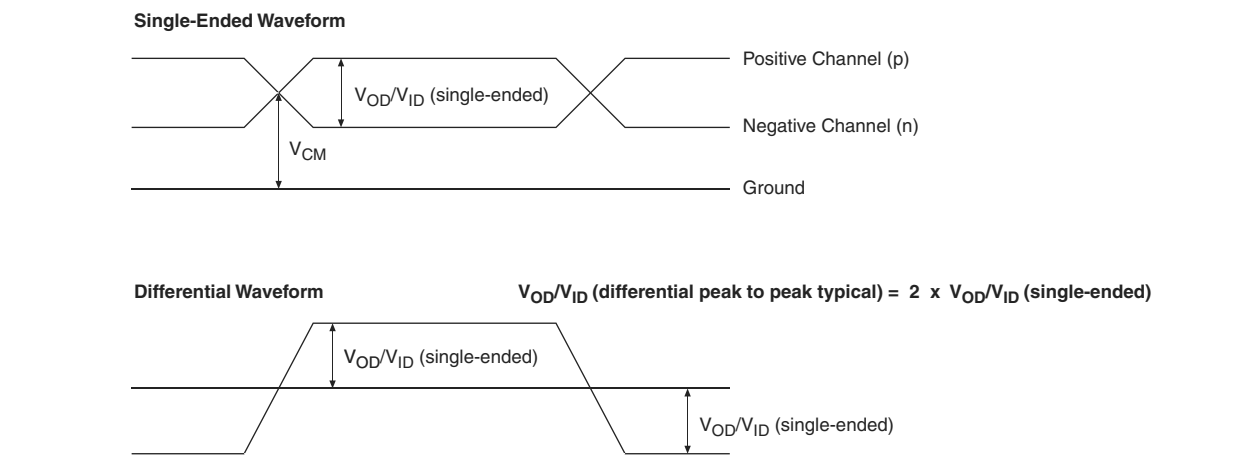


Figure 3 shows the Stratix V AC gain curves for GX channels.

**Figure 3. AC Gain Curves for GX Channels (full bandwidth)**



Stratix V GT devices contain both GX and GT channels. All transceiver specifications for the GX channels not listed in Table 28 are the same as those listed in Table 23.

Table 28 lists the Stratix V GT transceiver specifications.



**Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5) <sup>(1)</sup>**

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors <sup>(7)</sup>	GT channels	—	100	—	—	100	—	$\Omega$
Differential on-chip termination resistors for GX channels <sup>(19)</sup>	85- $\Omega$ setting	—	85 $\pm$ 30%	—	—	85 $\pm$ 30%	—	$\Omega$
	100- $\Omega$ setting	—	100 $\pm$ 30%	—	—	100 $\pm$ 30%	—	$\Omega$
	120- $\Omega$ setting	—	120 $\pm$ 30%	—	—	120 $\pm$ 30%	—	$\Omega$
	150- $\Omega$ setting	—	150 $\pm$ 30%	—	—	150 $\pm$ 30%	—	$\Omega$
V <sub>ICM</sub> (AC coupled)	GT channels	—	650	—	—	650	—	mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 0.85 V or 0.9 V	—	600	—	—	600	—	mV
	VCCR_GXB = 1.0 V full bandwidth	—	700	—	—	700	—	mV
	VCCR_GXB = 1.0 V half bandwidth	—	750	—	—	750	—	mV
t <sub>LTR</sub> <sup>(9)</sup>	—	—	—	10	—	—	10	$\mu$ s
t <sub>LTD</sub> <sup>(10)</sup>	—	4	—	—	4	—	—	$\mu$ s
t <sub>LTD_manual</sub> <sup>(11)</sup>	—	4	—	—	4	—	—	$\mu$ s
t <sub>LTR_LTD_manual</sub> <sup>(12)</sup>	—	15	—	—	15	—	—	$\mu$ s
Run Length	GT channels	—	—	72	—	—	72	CID
	GX channels	<sup>(8)</sup>						
CDR PPM	GT channels	—	—	1000	—	—	1000	$\pm$ PPM
	GX channels	<sup>(8)</sup>						
Programmable equalization (AC Gain) <sup>(5)</sup>	GT channels	—	—	14	—	—	14	dB
	GX channels	<sup>(8)</sup>						
Programmable DC gain <sup>(6)</sup>	GT channels	—	—	7.5	—	—	7.5	dB
	GX channels	<sup>(8)</sup>						
Differential on-chip termination resistors <sup>(7)</sup>	GT channels	—	100	—	—	100	—	$\Omega$
<b>Transmitter</b>								
Supported I/O Standards	—	1.4-V and 1.5-V PCML						
Data rate (Standard PCS)	GX channels	600	—	8500	600	—	8500	Mbps
Data rate (10G PCS)	GX channels	600	—	12,500	600	—	12,500	Mbps

Figure 4 shows the differential transmitter output waveform.

**Figure 4. Differential Transmitter/Receiver Output/Input Waveform**



Figure 5 shows the Stratix V AC gain curves for GT channels.

**Figure 5. AC Gain Curves for GT Channels**

Figure 6 shows the Stratix V DC gain curves for GT channels.

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**Figure 6. DC Gain Curves for GT Channels**

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**Transceiver Characterization**

This section summarizes the Stratix V transceiver characterization results for compliance with the following protocols:

- Interlaken
- 40G (XLAUI)/100G (CAUI)
- 10GBase-KR
- QSGMII
- XAUI
- SFI
- Gigabit Ethernet (Gbe / GIGE)
- SPAUI
- Serial Rapid IO (SRIO)
- CPRI
- OBSAI
- Hyper Transport (HT)
- SATA
- SAS
- CEI

## PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85°C) and the industrial junction temperature range (–40° to 100°C).

**Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)**

Symbol	Parameter	Min	Typ	Max	Unit
$f_{IN}$	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	—	800 <sup>(1)</sup>	MHz
	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	—	800 <sup>(1)</sup>	MHz
	Input clock frequency (C4, I4 speed grades)	5	—	650 <sup>(1)</sup>	MHz
$f_{INPFD}$	Input frequency to the PFD	5	—	325	MHz
$f_{FINPFD}$	Fractional Input clock frequency to the PFD	50	—	160	MHz
$f_{VCO}$ <sup>(9)</sup>	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	—	1600	MHz
	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	—	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
$t_{EINDUTY}$	Input clock or external feedback clock input duty cycle	40	—	60	%
$f_{OUT}$	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	—	—	717 <sup>(2)</sup>	MHz
	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	—	—	650 <sup>(2)</sup>	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)	—	—	580 <sup>(2)</sup>	MHz
$f_{OUT\_EXT}$	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)	—	—	800 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C3, I3, I3L speed grades)	—	—	667 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C4, I4 speed grades)	—	—	553 <sup>(2)</sup>	MHz
$t_{OUTDUTY}$	Duty cycle for a dedicated external clock output (when set to 50%)	45	50	55	%
$t_{FCOMP}$	External feedback clock compensation time	—	—	10	ns
$f_{DYCONFIGCLK}$	Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code>	—	—	100	MHz
$t_{LOCK}$	Time required to lock from the end-of-device configuration or deassertion of <code>areset</code>	—	—	1	ms
$t_{DLOCK}$	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	—	—	1	ms
$f_{CLBW}$	PLL closed-loop low bandwidth	—	0.3	—	MHz
	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth <sup>(7)</sup>	—	4	—	MHz
$t_{PLL\_PSERR}$	Accuracy of PLL phase shift	—	—	±50	ps
$t_{ARESET}$	Minimum pulse width on the <code>areset</code> signal	10	—	—	ns

**Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Transmitter														
True Differential I/O Standards - f <sub>HSDR</sub> (data rate)	SERDES factor J = 3 to 10 <sup>(9), (11), (12), (13), (14), (15), (16)</sup>	(6)	—	1600	(6)	—	1434	(6)	—	1250	(6)	—	1050	Mbps
	SERDES factor J ≥ 4  LVDS TX with DPA <sup>(12), (14), (15), (16)</sup>	(6)	—	1600	(6)	—	1600	(6)	—	1600	(6)	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f <sub>HSDR</sub> (data rate) <sup>(10)</sup>	SERDES factor J = 4 to 10 <sup>(17)</sup>	(6)	—	1100	(6)	—	1100	(6)	—	840	(6)	—	840	Mbps
t <sub>x Jitter</sub> - True Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	160	—	—	160	—	—	160	—	—	160	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.1	—	—	0.1	—	—	0.1	—	—	0.1	UI
t <sub>x Jitter</sub> - Emulated Differential I/O Standards with Three External Output Resistor Network	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	300	—	—	300	—	—	300	—	—	325	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.2	—	—	0.2	—	—	0.2	—	—	0.25	UI

Figure 7 shows the dynamic phase alignment (DPA) lock time specifications with the DPA PLL calibration option enabled.

**Figure 7. DPA Lock Time Specification with DPA PLL Calibration Enabled**



Table 37 lists the DPA lock time specifications for Stratix V devices.

**Table 37. DPA Lock Time Specifications for Stratix V GX Devices Only <sup>(1), (2), (3)</sup>**

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions <sup>(4)</sup>	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

**Notes to Table 37:**

- (1) The DPA lock time is for one channel.
- (2) One data transition is defined as a 0-to-1 or 1-to-0 transition.
- (3) The DPA lock time stated in this table applies to both commercial and industrial grade.
- (4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 8 shows the LVDS soft-clock data recovery (CDR)/DPA sinusoidal jitter tolerance specification for a data rate  $\geq 1.25$  Gbps. Table 38 lists the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate  $\geq 1.25$  Gbps.

**Figure 8. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate  $\geq 1.25$  Gbps**



## Duty Cycle Distortion (DCD) Specifications

Table 44 lists the worst-case DCD for Stratix V devices.

**Table 44. Worst-Case DCD on Stratix V I/O Pins <sup>(1)</sup>**

Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4, I4		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	45	55	45	55	%

**Note to Table 44:**

(1) The DCD numbers do not cover the core clock network.

## Configuration Specification

### POR Delay Specification

Power-on reset (POR) delay is defined as the delay between the time when all the power supplies monitored by the POR circuitry reach the minimum recommended operating voltage to the time when the nSTATUS is released high and your device is ready to begin configuration.



For more information about the POR delay, refer to the *Hot Socketing and Power-On Reset in Stratix V Devices* chapter.

Table 45 lists the fast and standard POR delay specification.

**Table 45. Fast and Standard POR Delay Specification <sup>(1)</sup>**

POR Delay	Minimum	Maximum
Fast	4 ms	12 ms
Standard	100 ms	300 ms

**Note to Table 45:**

(1) You can select the POR delay based on the MSEL settings as described in the MSEL Pin Settings section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

### JTAG Configuration Specifications

Table 46 lists the JTAG timing parameters and values for Stratix V devices.

**Table 46. JTAG Timing Parameters and Values for Stratix V Devices**

Symbol	Description	Min	Max	Unit
t <sub>JCP</sub>	TCK clock period <sup>(2)</sup>	30	—	ns
t <sub>JCP</sub>	TCK clock period <sup>(2)</sup>	167	—	ns
t <sub>JCH</sub>	TCK clock high time <sup>(2)</sup>	14	—	ns
t <sub>JCL</sub>	TCK clock low time <sup>(2)</sup>	14	—	ns
t <sub>JPSU (TDI)</sub>	TDI JTAG port setup time	2	—	ns
t <sub>JPSU (TMS)</sub>	TMS JTAG port setup time	3	—	ns

**Table 49. DCLK-to-DATA[] Ratio <sup>(1)</sup> (Part 2 of 2)**

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×32	Disabled	Disabled	1
	Disabled	Enabled	4
	Enabled	Disabled	8
	Enabled	Enabled	8

**Note to Table 49:**

- (1) Depending on the DCLK-to-DATA[] ratio, the host must send a DCLK frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the DCLK-to-DATA[] ratio is 2, the DCLK frequency must be 2 times the data rate in Wps. Stratix V devices use the additional clock cycles to decrypt and decompress the configuration data.



If the DCLK-to-DATA[] ratio is greater than 1, at the end of configuration, you can only stop the DCLK (DCLK-to-DATA[] ratio – 1) clock cycles after the last data is latched into the Stratix V device.

Figure 11 shows the configuration interface connections between the Stratix V device and a MAX II or MAX V device for single device configuration.

**Figure 11. Single Device FPP Configuration Using an External Host****Notes to Figure 11:**

- (1) Connect the resistor to a supply that provides an acceptable input signal for the Stratix V device.  $V_{CCPGM}$  must be high enough to meet the  $V_{IH}$  specification of the I/O on the device and the external host. Altera recommends powering up all configuration system I/Os with  $V_{CCPGM}$ .
- (2) You can leave the nCEO pin unconnected or use it as a user I/O pin when it does not feed another device's nCE pin.
- (3) The MSEL pin settings vary for different data width, configuration voltage standards, and POR delay. To connect MSEL, refer to the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (4) If you use FPP ×8, use DATA[7..0]. If you use FPP ×16, use DATA[15..0].



**Figure 13. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1 (1), (2)****Notes to Figure 13:**

- (1) Use this timing waveform and parameters when the DCLK-to-DATA[] ratio is >1. To find out the DCLK-to-DATA[] ratio for your system, refer to Table 49 on page 55.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nSTATUS low for the time as specified by the POR delay.
- (4) After power-up, before and during configuration, CONF\_DONE is low.
- (5) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (6) "r" denotes the DCLK-to-DATA[] ratio. For the DCLK-to-DATA[] ratio based on the decompression and the design security feature enable settings, refer to Table 49 on page 55.
- (7) If needed, pause DCLK by holding it low. When DCLK restarts, the external host must provide data on the DATA[31..0] pins prior to sending the first DCLK rising edge.
- (8) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (9) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.

Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [ ] ratio is more than 1.

**Table 51. FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[ ] Ratio is >1 <sup>(1)</sup>**

Symbol	Parameter	Minimum	Maximum	Units
$t_{CF2CD}$	nCONFIG low to CONF_DONE low	—	600	ns
$t_{CF2ST0}$	nCONFIG low to nSTATUS low	—	600	ns
$t_{CFG}$	nCONFIG low pulse width	2	—	$\mu$ s
$t_{STATUS}$	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	$\mu$ s
$t_{CF2ST1}$	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	$\mu$ s
$t_{CF2CK}$ <sup>(5)</sup>	nCONFIG high to first rising edge on DCLK	1,506	—	$\mu$ s
$t_{ST2CK}$ <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	$\mu$ s
$t_{DSU}$	DATA [ ] setup time before rising edge on DCLK	5.5	—	ns
$t_{DH}$	DATA [ ] hold time after rising edge on DCLK	$N-1/f_{DCLK}$ <sup>(5)</sup>	—	s
$t_{CH}$	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CL}$	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CLK}$	DCLK period	$1/f_{MAX}$	—	s
$f_{MAX}$	DCLK frequency (FPP $\times 8/\times 16$ )	—	125	MHz
	DCLK frequency (FPP $\times 32$ )	—	100	MHz
$t_R$	Input rise time	—	40	ns
$t_F$	Input fall time	—	40	ns
$t_{CD2UM}$	CONF_DONE high to user mode <sup>(3)</sup>	175	437	$\mu$ s
$t_{CD2CU}$	CONF_DONE high to CLKUSR enabled	$4 \times$ maximum DCLK period	—	—
$t_{CD2UMC}$	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times \text{CLKUSR period})$ <sup>(4)</sup>	—	—

**Notes to Table 51:**

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (5) N is the DCLK-to-DATA ratio and  $f_{DCLK}$  is the DCLK frequency the system is operating.
- (6) If nSTATUS is monitored, follow the  $t_{ST2CK}$  specification. If nSTATUS is not monitored, follow the  $t_{CF2CK}$  specification.

Table 60. Glossary (Part 3 of 4)

Letter	Subject	Definitions
S	SW (sampling window)	<p>Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown:</p>
	Single-ended voltage referenced I/O standard	<p>The JEDEC standard for <b>SSTL</b> and <b>HSTL</b> I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state.</p> <p>The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing:</p> <p><i>Single-Ended Voltage Referenced I/O Standard</i></p>
T	$t_c$	High-speed receiver and transmitter input and output clock period.
	TCCS (channel-to-channel-skew)	The timing difference between the fastest and slowest output edges, including $t_{CO}$ variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under <b>SW</b> in this table).
	$t_{DUTY}$	<p>High-speed I/O block—Duty cycle on the high-speed transmitter output clock.</p> <p><b>Timing Unit Interval (TUI)</b></p> <p>The timing budget allowed for skew, propagation delays, and the data sampling window. (TUI = <math>1/(\text{receiver input clock frequency multiplication factor}) = t_c/w</math>)</p>
	$t_{FALL}$	Signal high-to-low transition time (80-20%)
	$t_{INCCJ}$	Cycle-to-cycle jitter tolerance on the PLL clock input.
	$t_{OUTPJ\_IO}$	Period jitter on the general purpose I/O driven by a PLL.
	$t_{OUTPJ\_DC}$	Period jitter on the dedicated clock output driven by a PLL.
	$t_{RISE}$	Signal low-to-high transition time (20-80%)
U	—	—

**Table 61. Document Revision History (Part 2 of 3)**

Date	Version	Changes
November 2014	3.3	<ul style="list-style-type: none"> <li>■ Added the I3YY speed grade and changed the data rates for the GX channel in Table 1.</li> <li>■ Added the I3YY speed grade to the <math>V_{CC}</math> description in Table 6.</li> <li>■ Added the I3YY speed grade to <math>V_{CCHIP\_L}</math>, <math>V_{CCHIP\_R}</math>, <math>V_{CCHSSI\_L}</math>, and <math>V_{CCHSSI\_R}</math> descriptions in Table 7.</li> <li>■ Added 240-<math>\Omega</math> to Table 11.</li> <li>■ Changed CDR PPM tolerance in Table 23.</li> <li>■ Added additional max data rate for fPLL in Table 23.</li> <li>■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 25.</li> <li>■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 26.</li> <li>■ Changed CDR PPM tolerance in Table 28.</li> <li>■ Added additional max data rate for fPLL in Table 28.</li> <li>■ Changed the mode descriptions for MLAB and M20K in Table 33.</li> <li>■ Changed the Max value of <math>f_{HCLK\_OUT}</math> for the C2, C2L, I2, I2L speed grades in Table 36.</li> <li>■ Changed the frequency ranges for C1 and C2 in Table 39.</li> <li>■ Changed the .rbf file sizes for 5SGSD6 and 5SGSD8 in Table 47.</li> <li>■ Added note about nSTATUS to Table 50, Table 51, Table 54.</li> <li>■ Changed the available settings in Table 58.</li> <li>■ Changed the note in “Periphery Performance”.</li> <li>■ Updated the “I/O Standard Specifications” section.</li> <li>■ Updated the “Raw Binary File Size” section.</li> <li>■ Updated the receiver voltage input range in Table 22.</li> <li>■ Updated the max frequency for the LVDS clock network in Table 36.</li> <li>■ Updated the DCLK note to Figure 11.</li> <li>■ Updated Table 23 <math>VO_{CM}</math> (DC Coupled) condition.</li> <li>■ Updated Table 6 and Table 7.</li> <li>■ Added the DCLK specification to Table 55.</li> <li>■ Updated the notes for Table 47.</li> <li>■ Updated the list of parameters for Table 56.</li> </ul>
November 2013	3.2	■ Updated Table 28
November 2013	3.1	■ Updated Table 33
November 2013	3.0	■ Updated Table 23 and Table 28
October 2013	2.9	■ Updated the “Transceiver Characterization” section
October 2013	2.8	<ul style="list-style-type: none"> <li>■ Updated Table 3, Table 12, Table 14, Table 19, Table 20, Table 23, Table 24, Table 28, Table 30, Table 31, Table 32, Table 33, Table 36, Table 39, Table 40, Table 41, Table 42, Table 47, Table 53, Table 58, and Table 59</li> <li>■ Added Figure 1 and Figure 3</li> <li>■ Added the “Transceiver Characterization” section</li> <li>■ Removed all “Preliminary” designations.</li> </ul>

**Table 61. Document Revision History (Part 3 of 3)**

Date	Version	Changes
May 2013	2.7	<ul style="list-style-type: none"> <li>■ Updated Table 2, Table 6, Table 7, Table 20, Table 23, Table 27, Table 47, Table 60</li> <li>■ Added Table 24, Table 48</li> <li>■ Updated Figure 9, Figure 10, Figure 11, Figure 12</li> </ul>
February 2013	2.6	<ul style="list-style-type: none"> <li>■ Updated Table 7, Table 9, Table 20, Table 23, Table 27, Table 30, Table 31, Table 35, Table 46</li> <li>■ Updated “Maximum Allowed Overshoot and Undershoot Voltage”</li> </ul>
December 2012	2.5	<ul style="list-style-type: none"> <li>■ Updated Table 3, Table 6, Table 7, Table 8, Table 23, Table 24, Table 25, Table 27, Table 30, Table 32, Table 35</li> <li>■ Added Table 33</li> <li>■ Added “Fast Passive Parallel Configuration Timing”</li> <li>■ Added “Active Serial Configuration Timing”</li> <li>■ Added “Passive Serial Configuration Timing”</li> <li>■ Added “Remote System Upgrades”</li> <li>■ Added “User Watchdog Internal Circuitry Timing Specification”</li> <li>■ Added “Initialization”</li> <li>■ Added “Raw Binary File Size”</li> </ul>
June 2012	2.4	<ul style="list-style-type: none"> <li>■ Added Figure 1, Figure 2, and Figure 3.</li> <li>■ Updated Table 1, Table 2, Table 3, Table 6, Table 11, Table 22, Table 23, Table 27, Table 29, Table 30, Table 31, Table 32, Table 35, Table 38, Table 39, Table 40, Table 41, Table 43, Table 56, and Table 59.</li> <li>■ Various edits throughout to fix bugs.</li> <li>■ Changed title of document to <i>Stratix V Device Datasheet</i>.</li> <li>■ Removed document from the Stratix V handbook and made it a separate document.</li> </ul>
February 2012	2.3	<ul style="list-style-type: none"> <li>■ Updated Table 1–22, Table 1–29, Table 1–31, and Table 1–31.</li> </ul>
December 2011	2.2	<ul style="list-style-type: none"> <li>■ Added Table 2–31.</li> <li>■ Updated Table 2–28 and Table 2–34.</li> </ul>
November 2011	2.1	<ul style="list-style-type: none"> <li>■ Added Table 2–2 and Table 2–21 and updated Table 2–5 with information about Stratix V GT devices.</li> <li>■ Updated Table 2–11, Table 2–13, Table 2–20, and Table 2–25.</li> <li>■ Various edits throughout to fix SPRs.</li> </ul>
May 2011	2.0	<ul style="list-style-type: none"> <li>■ Updated Table 2–4, Table 2–18, Table 2–19, Table 2–21, Table 2–22, Table 2–23, and Table 2–24.</li> <li>■ Updated the “DQ Logic Block and Memory Output Clock Jitter Specifications” title.</li> <li>■ Chapter moved to Volume 1.</li> <li>■ Minor text edits.</li> </ul>
December 2010	1.1	<ul style="list-style-type: none"> <li>■ Updated Table 1–2, Table 1–4, Table 1–19, and Table 1–23.</li> <li>■ Converted chapter to the new template.</li> <li>■ Minor text edits.</li> </ul>
July 2010	1.0	Initial release.